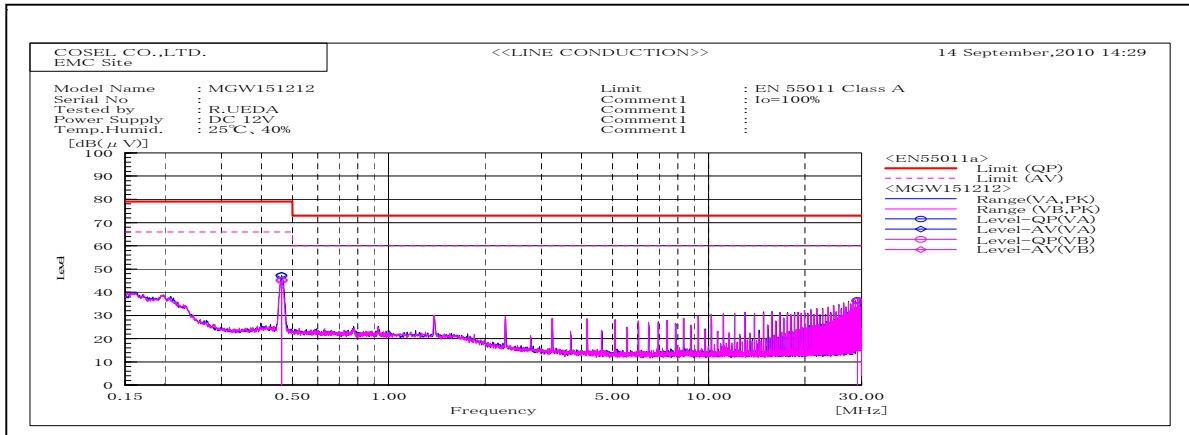
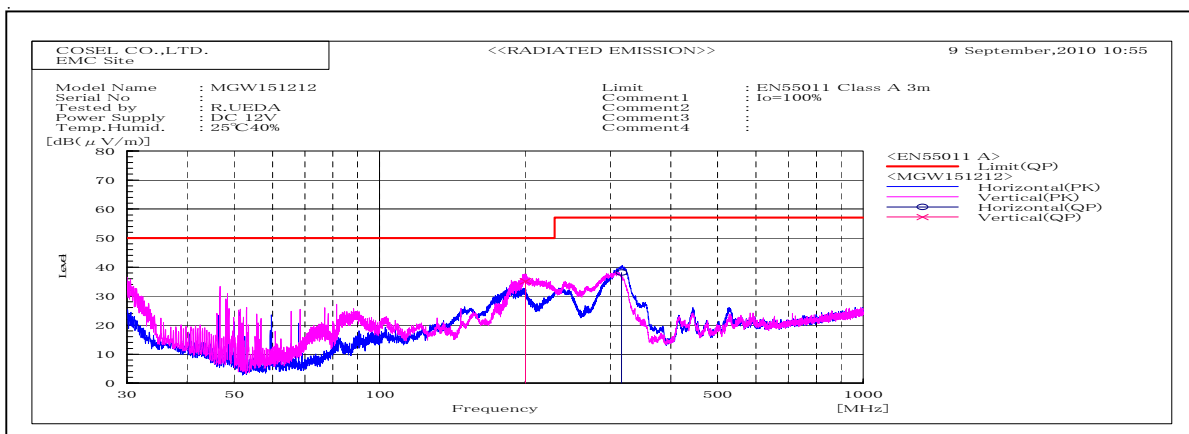


DATA SHEET		Date	21-Sep-10
Model	MGW151212	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	R.Ueda



Frequency MHz	Harm	Line Phase	Reading dB(uV)		Factor dB	Level dB(uV)		Limit dB(uV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.46265		VB	35.1	35.2	10	45.1	45.2	79	66	33.9	20.8	Pass	
0.46255		VA	37	37.2	10.1	47.1	47.3	79	66	31.9	18.7	Pass	
29.1461		VB	25.2	25.4	11	36.2	36.4	73	60	36.8	23.6	Pass	
29.14455		VA	25.7	25.8	10.7	36.4	36.5	73	60	36.6	23.5	Pass	



Frequency MHz	Polarization	Stability	Reading dB(uV)		Space Loss dB	Level dB(mW)		Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	AV						
200.213	V	Stable	57.1		-22	35.1		50	14.9	Pass	110	202	
316.366	H	Stable	55.3		-17.2	38.1		57	18.9	Pass	121	8	

DATA SHEET

Model	Circuit used for measurement
Test	EMI Line conduction & Radiated emission

1. Line conduction



2. Radiated emission

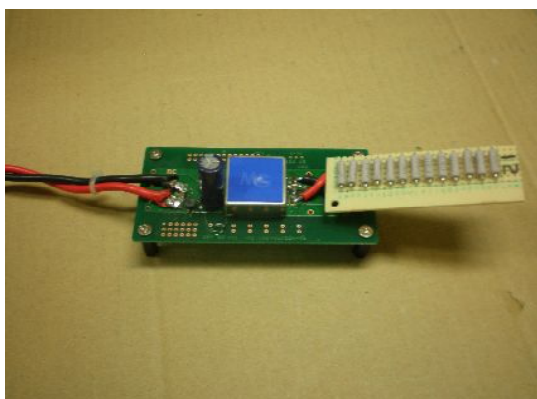


Conditions

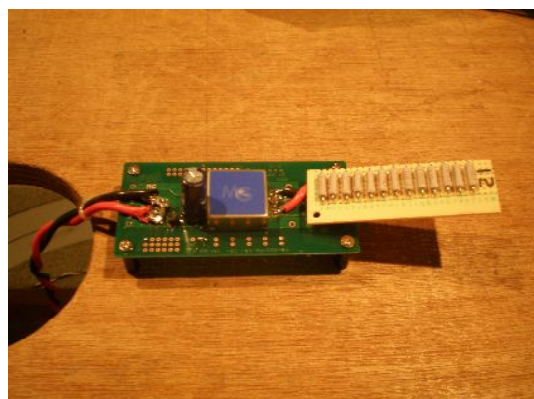
Test : EMI
Model Name : MGS1512□□/MGW1512□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

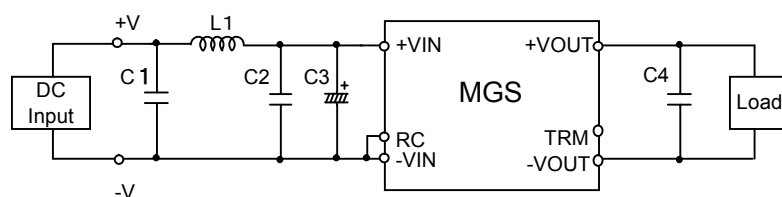


Fig.1 Testing circuitry 1

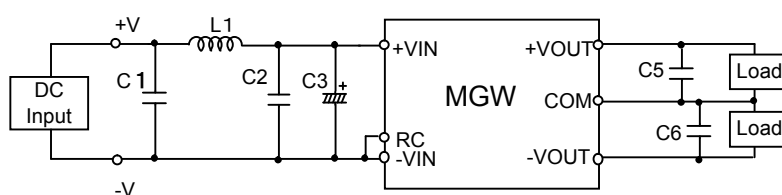


Fig.2 Testing circuitry 2

L1	:	0.5 μ H	CI4C-0R5	(KORIN ELECTRONICS)
C1,C2	:	25V 10 μ F	CM316X5R106K25A	(KYOCERA)
C3	:	50V 220 μ F	LXY50VB220M	(NIPPON CHEMI-CON)
C4,C5,C6	:	25V 22 μ F	CM32X5R226K25A	(KYOCERA)